

Abstract of the Disclosure

A contact for use in a contact set assembly. The contact spans a space which separates a lead of an integrated circuit to be tested and a pad of a load board interfacing with the tester. The contact construction provides electrical communication between integrated circuit lead and the load board pad. Included is an insulating lamina which comprises, in part, a contact. A conductive lamina overlies at least a portion of the insulating lamina. The laminar construction and size and shape of conductive traces applied to a ceramic lamina enable parameters of the contact to be provided.